74F38

Quad 2-input NAND buffer (open collector) Rev. 3 — 10 January 2014

Product data sheet

General description 1.

The 74F38 provides four 2-input NAND functions with open-collector outputs.

2. **Features and benefits**

■ Industrial temperature range available (–40 °C to +85 °C)

Ordering information 3.

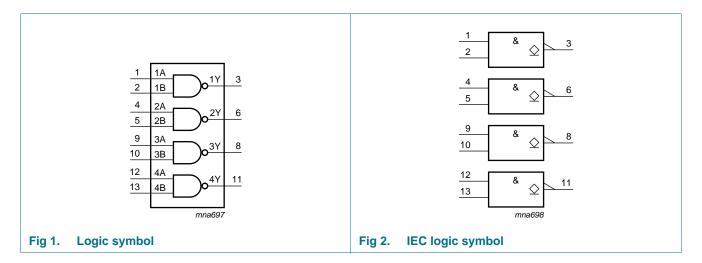
Table 1. **Ordering information**

Type number Package							
	Temperature range	Name	Description	Version			
N74F38N	0 °C to +70 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1			
174F38N	–40 °C to +85 °C						
N74F38D	0 °C to +70 °C	SO14	plastic small outline package; 14 leads; body width	SOT108-1			
174F38D	–40 °C to +85 °C		3.9 mm				



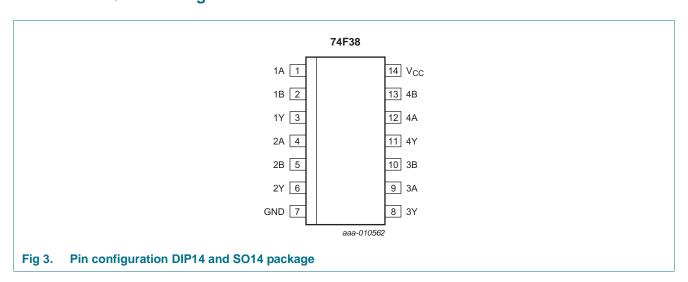
Quad 2-input NAND buffer (open collector)

4. Functional diagram



5. Pinning information

5.1 Pinning



Quad 2-input NAND buffer (open collector)

5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description	Unit load HIGH/LOW	Load value ^{[1][2]} HIGH/LOW
1A, 2A, 3A, 4A	1, 4, 9, 12	data input	1.0/2.0	20 μA/1.2 mA
1B, 2B, 3B, 4B	2, 5, 10, 13	data input	1.0/2.0	20 μA/1.2 mA
1Y, 2Y, 3Y, 4Y	3, 6, 8, 11	data output	OC/106.7	OC/64 mA
GND	7	ground (0 V)	-	-
V _{CC}	14	supply voltage	-	-

^[1] One FAST Unit Load (UL) is defined as 20 μA in HIGH state, 0.6 mA in LOW state.

6. Functional description

Table 3. Function table[1]

Input	Output	
nA	nB	nY
L	L	Н
L	Н	Н
Н	L	Н
Н	Н	L

^[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+7.0	V
VI	input voltage		<u>[1]</u> –0.5	+7.0	V
Vo	output voltage	output in HIGH-state	<u>[1]</u> –0.5	V_{CC}	V
I _{IK}	input clamping current	V _I < 0 V	-30	+5	mA
Io	output current	output in LOW-state	-	128	mA
T _{amb}	ambient temperature	in free-air	[2]		
		commercial	0	70	°C
		industrial	-40	+85	°C
T _{stg}	storage temperature		-65	+150	°C

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^[2] OC = open collector.

^[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

Quad 2-input NAND buffer (open collector)

8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CC}	supply voltage		4.5	5.0	5.5	V
V_{IH}	HIGH-level input voltage		2.0	-	-	V
V_{IL}	LOW-level input voltage		-	-	8.0	V
V_{OH}	HIGH-level output voltage		-	-	4.5	V
I_{IK}	input clamping current		-18	-	-	mA
I _{OL}	LOW-level output current		-	-	64	mA

9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions		25 °C		0 °C to	+70 °C	Unit
			Min	Typ[1]	Max	Min	Max	
V_{IK}	input clamping voltage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$	-1.2	-0.73	-	-1.2	-	V
V _{OL} LOW-level output voltage		$V_{CC} = 4.5 \text{ V}; V_{IL} = 0.8 \text{ V}; V_{IH} = 2.0 \text{ V}$						
		I _{OL} = 64 mA						
		V _{CC} = ±10 %	-	-	-	-	0.55	V
		V _{CC} = ±5 %	-	0.42	-	-	0.55	V
I	input leakage current	$V_{CC} = 0 \text{ V}; V_I = 7.0 \text{ V}$	-	-	-	-	100	μΑ
I _{IH}	HIGH-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 2.7 \text{ V}$	-	-	-	-	20	μΑ
I _{IL}	LOW-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 0.5 \text{ V}$	-	-	-	-20	-	μΑ
I _{CC}	supply current	V _{CC} = 5.5 V						
		$V_I = GND$	-	4	-	-	7	mΑ
		V _I = 4.5 V	-	22	-	-	30	mΑ

^[1] All typical values are measured at $V_{CC} = 5 \text{ V}$.

10. Dynamic characteristics

Table 7. Dynamic characteristics

GND = 0 V. Test circuit is shown in Figure 6.

Symbol	Parameter	Conditions	25 °C; V _{CC} = 5.0 V			0 °C to +70 V _{CC} = 5.0 °	•	-40 °C to $V_{CC} = 5.0$ °	Unit	
			Min	Тур	Max	Min	Max	Min	Max	
t _{PZL}	OFF-state to LOW propagation delay	nA, nB to nY; see Figure 4	1.5	3.0	5.0	1.5	5.5	1.5	6.0	ns
t _{PLZ}	LOW to OFF-state propagation delay	nA, nB to nY; see <u>Figure 4</u>	7.5	10.0	12.5	7.5	13.0	7.5	14.5	ns

Quad 2-input NAND buffer (open collector)

11. Waveforms

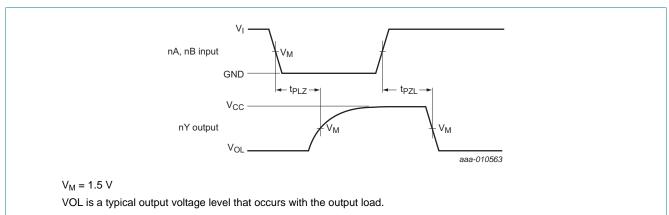
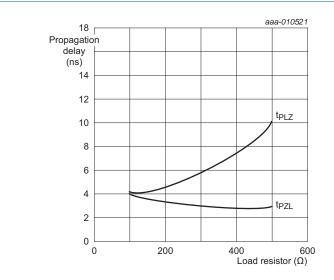


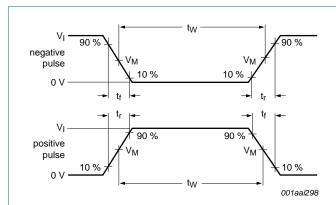
Fig 4. Propagation delay for inverting outputs

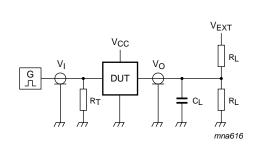


When using open collector parts, the value of the pull-up resistor greatly affects the value of the t_{PLZ} . For example, changing the specified pull-up resistor value from 500 Ω to 100 Ω improves the t_{PLZ} up to 50% with only a slight increase in the t_{PZL} . However, if the value of the pull-up resistor is changed, the user must ensure that the total t_{OL} current through the resistor and the total t_{IL} of the receivers, does not exceed the t_{IL} minimum specification.

Fig 5. Typical propagation delays versus load for open collector outputs

Quad 2-input NAND buffer (open collector)





b. Test circuit

a. Input pulse definition

Test data is given in Table 8.

Test circuit definitions:

R_L = Load resistance.

 C_L = Load capacitance including jig and probe capacitance.

 R_T = Termination resistance should be equal to output impedance Z_0 of the pulse generator.

 V_{EXT} = Test voltage for switching times.

Fig 6. Load circuitry for switching times

Table 8. Test data

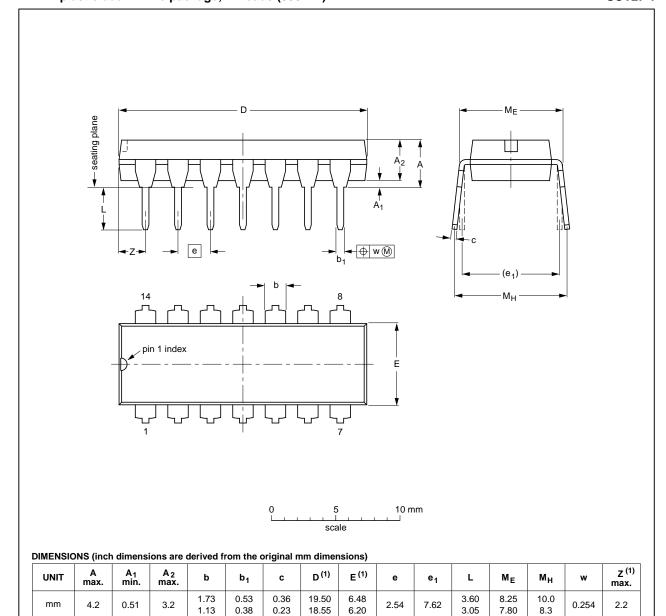
Input			Load	V _{EXT}		
V_{l}	f _i	t _W	t _r , t _f	CL	R _L	t _{PZL} , t _{PLZ}
3.0 V	1 MHz	500 ns	\leq 2.5 ns	50 pF	500 Ω	7.0 V

Quad 2-input NAND buffer (open collector)

12. Package outline

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



inches

0.17

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

0.068

0.044

0.021

0.015

0.014

0.009

0.77

0.14

0.32

0.39

OUTLINE		EUROPEAN	ISSUE DATE			
VERSION	VERSION IEC JEDEC JEITA			PROJECTION	ISSUE DATE	
SOT27-1	050G04	MO-001	SC-501-14			99-12-27 03-02-13

0.1

0.3

Fig 7. Package outline SOT27-1 (DIP14)

0.02

0.13

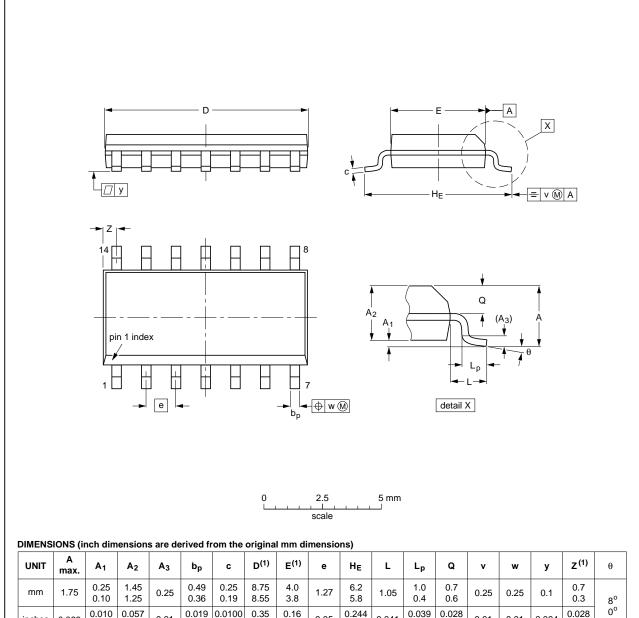
0.087

0.01

NXP Semiconductors

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	V	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01	ı	0.0100 0.0075		0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016		0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		EUROPEAN	ISSUE DATE				
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT108-1	076E06	MS-012				99-12-27 03-02-19	

Fig 8. Package outline SOT108-1 (SO14)

All information provided in this document is subject to legal disclaimers.

© NXP B.V. 2014. All rights reserved.

Quad 2-input NAND buffer (open collector)

13. Abbreviations

Table 9. Abbreviations

Acronym	Description
CDM	Charged-Device Model
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

14. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
74F38 v.3	20140110	Product data sheet	-	74F38 v.2		
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 					
	 Legal texts have been adapted to the new company name where appropriate. 					
	General update of values					
74F38 v.2	19901004	Product specification	-	-		

Quad 2-input NAND buffer (open collector)

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

15.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

Product specification — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

15.3 Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. NXP Semiconductors takes no responsibility for the content in this document if provided by an information source outside of NXP Semiconductors.

In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of NXP Semiconductors.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors and its suppliers accept no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

Terms and conditions of commercial sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

74F38

Quad 2-input NAND buffer (open collector)

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

Non-automotive qualified products — Unless this data sheet expressly states that this specific NXP Semiconductors product is automotive qualified, the product is not suitable for automotive use. It is neither qualified nor tested in accordance with automotive testing or application requirements. NXP Semiconductors accepts no liability for inclusion and/or use of non-automotive qualified products in automotive equipment or applications.

In the event that customer uses the product for design-in and use in automotive applications to automotive specifications and standards, customer (a) shall use the product without NXP Semiconductors' warranty of the product for such automotive applications, use and specifications, and (b) whenever customer uses the product for automotive applications beyond

NXP Semiconductors' specifications such use shall be solely at customer's own risk, and (c) customer fully indemnifies NXP Semiconductors for any liability, damages or failed product claims resulting from customer design and use of the product for automotive applications beyond NXP Semiconductors' standard warranty and NXP Semiconductors' product specifications.

Translations — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

15.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

16. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

Quad 2-input NAND buffer (open collector)

17. Contents

1	General description 1
2	Features and benefits
3	Ordering information 1
4	Functional diagram 2
5	Pinning information 2
5.1	Pinning
5.2	Pin description
6	Functional description 3
7	Limiting values 3
8	Recommended operating conditions 4
9	Static characteristics 4
10	Dynamic characteristics 4
11	Waveforms
12	Package outline
13	Abbreviations 9
14	Revision history 9
15	Legal information
15.1	Data sheet status
15.2	Definitions
15.3	Disclaimers
15.4	Trademarks
16	Contact information 11
17	Contents

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for Gate Drivers category:

Click to view products by NXP manufacturer:

Other Similar products are found below:

00028 00053P0231 8967380000 56956 CR7E-30DB-3.96E(72) 57.404.7355.5 LT4936 57.904.0755.0 5801-0903 5803-0901 5811-0902 5813-0901 58410 00576P0030 00581P0070 5882900001 00103P0020 00600P0005 00-9050-LRPP 00-9090-RDPP 5951900000 01-1003W-10/32-15 LTILA6E-1S-WH-RC-FN12VXCR1 0131700000 00-2240 LTP70N06 LVP640 0158-624-00 5J0-1000LG-SIL 020017-13 LY1D-2-5S-AC120 LY2-0-US-AC120 LY2-US-AC240 LY3-UA-DC24 00-5150 00576P0020 00600P0010 LZNQ2M-US-DC5 LZNQ2-US-DC12 LZP40N10 00-8196-RDPP 00-8274-RDPP 00-8275-RDNP 00-8609-RDPP 00-8722-RDPP 00-8728-WHPP 00-8869-RDPP 00-9051-RDPP 00-9091-LRPP 00-9291-RDPP